

Amendments to the Claims

1. (CURRENTLY AMENDED) A data carrier (1)-that is arranged to receive a signal (S)-in a non-contacting manner and that has an electrical circuit-(2), to which circuit (2)-the signal (S)-can be fed and which circuit (2)-is arranged to generate a supply voltage (V)-for parts of the circuit (2)-by using the signal-(S), which circuit (2) comprises storage means (5)-that are arranged to store information capacitively, the information being represented by a value of an information voltage (UI)-arising at the storage means-(5), which value of the information voltage (UI)-is at most equal to the value of the supply voltage-(V), and which circuit (2)-has evaluation means (14)-to which the information voltage (UI)-can be fed and that are arranged to evaluate the information voltage-(UI), with the help of a comparison voltage-(UC), for the information represented by the information voltage-(UI), characterized in that comparison-voltage generating means (15)-that are arranged to generate and emit the comparison voltage (UC)-are implemented separately from the evaluation means-(14), and in that the evaluation means (14)-are arranged to receive the comparison voltage (UC)-from the comparison-voltage generating means-(15).

2. (CURRENTLY AMENDED) A data carrier (1)-as claimed in claim 1, characterized in that the evaluation means (14)-are formed by a difference amplifier stage-(16), which difference amplifier stage (16)-is intended to amplify the difference between the information voltage (UI)-and the comparison voltage-(UC).

3. (CURRENTLY AMENDED) A data carrier as claimed in claim 1, characterized in that the circuit (2)-has a test terminal (T)-from which a representation of the information voltage (UI)-can be picked off, and in that the evaluation means (14)-are arranged to make the information voltage (UI)-available at the test terminal (T)-in a way that can be controlled.

4. (CURRENTLY AMENDED) A data carrier (1)-as claimed in claim 1, characterized in that the comparison-voltage generating means (15)-are arranged to take account of a value of the supply voltage (V)-when generating the comparison voltage-(UC).

5. (CURRENTLY AMENDED) A data carrier (1)-as claimed in claim 1, characterized in that the comparison-voltage generating means (15)-are arranged to generate the comparison voltage (UC)-in a programmable manner.

6. (CURRENTLY AMENDED) A circuit (2)-for a data carrier-(1), which data carrier (1)-is arranged to receive a signal (S)-in a non-contacting manner, which circuit (2)-is arranged, by using the signal-(S), to generate a supply voltage (V)-for parts of the circuit-(2), which circuit (2)-comprises storage means (5)-that are arranged to store information capacitively, the information being represented by a value of an information voltage (UI)-arising at the storage means-(5), which value of the information voltage (UI)-is at most equal to the value of the supply voltage-(V), and which circuit (2)-has evaluation means (14)-to which the information voltage (UI)-can be fed and that are arranged to evaluate the information voltage-(UI), with the help of a comparison voltage-(UC), for the information represented by the information voltage-(UI), characterized in that comparison-voltage generating means (15)-that are arranged to generate and emit the comparison voltage (UC)-are implemented separately from the evaluation means-(14), and in that the evaluation means (14)-are arranged to receive the comparison voltage (UC)-from the comparison-voltage generating means-(15).

7. (CURRENTLY AMENDED) A circuit (2)-as claimed in claim 6, characterized in that the evaluation means (14)-are formed by a difference amplifier stage-(16), which difference amplifier stage (16)-is intended to amplify the difference between the information voltage (UI)-and the comparison voltage-(UC).

8. (CURRENTLY AMENDED) A circuit (2)-as claimed in claim 6, characterized in that the circuit (2)-has a test terminal (T)-from which a representation of the information voltage (UI)-can be picked off, and in that the evaluation means (14)-are arranged to make the information voltage (UI)-available at the test terminal (T)-in a way that can be controlled.

9. (CURRENTLY AMENDED) A circuit ~~(2)~~ as claimed in claim 6, characterized in that the information-voltage generating means ~~(15)~~ are arranged to take account of a value of the supply voltage ~~(V)~~ when generating the comparison voltage ~~(UC)~~.
10. (CURRENTLY AMENDED) A circuit ~~(2)~~ as claimed in claim 6, characterized in that the comparison-voltage generating means ~~(15)~~ are arranged to generate the comparison voltage ~~(UC)~~ in a programmable manner.
11. (CURRENTLY AMENDED) A circuit ~~(2)~~ as claimed in claim 6, characterized in that the circuit ~~(2)~~ is implemented in the form of an integrated circuit.